

Notice of References Cited	Application/Control No. 10/775,221	Applicant(s)/Patent Under Reexamination SAWANO, TETSUYA	
	Examiner Katrina Fujita	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,096,265	08-2006	Simpson et al.	709/226
*	B	US-7,043,255	05-2006	Tiwari, Anil	455/456.1
*	C	US-2004/0190023	09-2004	Aoyama, Tatsuya	358/001.9
*	D	US-2004/0228528	11-2004	Lao, Shihong	382/167
*	E	US-7,010,596	03-2006	Bantz et al.	709/224
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.